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ELECTRONIC INFORMATION DISCLOSURE STATEMENT

Electronic Version v18
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Title of Invention	METHODS FOR CORRELATING BACKSIDE AND FRONTSIDE DEFECTS DETECTED ON A SPECIMEN AND CLASSIFICATION OF BACKSIDE DEFECTS

Application Number: 10/678883
Confirmation Number: 2324
First Named Applicant: Kurt Haller
Attorney Docket Number: 5589-04901
Search string: (6104835 or 6233719 or 5991699 or 5208648 or 5220403 or 4599558 or 5644393 or 4618938 or 4556317 or 5563702).pn.

US Patent Documents

Note: Applicant is not required to submit a paper copy of cited US Patent Documents

init	Cite.No.	Patent No.	Date	Patentee	Kind	Class	Subclass
KL	1	6104835	2000-08-15	Han			
	2	6233719	2001-05-15	Hardikar et al.			
	3	5991699	1999-11-23	Kulkarni et al.			
	4	5208648	1993-05-04	Batchelder et al.			
	5	5220403	1993-06-15	Batchelder et al.			
	6	4599558	1986-07-08	Castellano, Jr. et al.			
	7	5644393	1997-07-01	Nakamura et al.			
	8	4618938	1986-10-21	Sandland et al.			
	9	4556317	1985-12-03	Sandland et al.			
KL	10	5563702	1996-10-08	Emery et al.			

Signature

Examiner Name	Date
Kwan Ming Lee	3/5/2005

Paper No. : 01294

Form PTO-1449 (modified) List of Patents and Publications For Applicant's Information Disclosure Statement (Use several sheets if necessary)	ATTY. DKT. NO. 5589-04901 APPLICANT: Haller FILING DATE: October 3, 2003	SERIAL NO. 10/678,883 GROUP: ~~2857~~ 2823

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U.S. PATENT DOCUMENTS

EXAM. INITIALS	REF. DES.	DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
Lee	A1	2003/0139838	2003-07-24	Marella			

FOREIGN PATENT DOCUMENTS

EXAM. INITIALS	REF. DES.	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUB CLASS	TRANSLATION YES/NO
Lee	A2	6-347415	1994-12-22	JP			Yes, Abstract
	A3	62-39705	1987-02-20	JP			Yes, Abstract
	A4	8-102479	1996-04-16	JP			Yes, Abstract
	A5	6-349908	1994-12-22	JP			Yes, Abstract
	A6	99/22310	1999-05-06	WO			
	A7	99/59200	1999-11-18	WO			
	A8	00/03234	2000-01-20	WO			
Lee	A9	01/40145	2001-06-07	WO			

OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)

Lee	A10	Otsu, "A Threshold Selection Method from Gray-Level Histograms," IEEE Transactions on Systems, Man, and Cybernetics, Vol. SMC-9, No. 1, January 1979, pp. 62-66.
Lee	A11	Cheema et al., "Wafer Back Side Inspection Applications for Yield Protection and Enhancement," presented at the Advanced Semiconductor Manufacturing Conference, Boston, MA, April 30, 2002, 8 pages.
Lee	A12	Diebold, Handbook of Silicon SemiconductorMetrology, © 2001 by Marcel Dekker, Inc., pp. 694-698.

EXAMINER: Kevin Min Lee DATE CONSIDERED: 3/5/2005

EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to the patent owner.